

Powder Diffraction

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Volume 7 Number 1 March 1992

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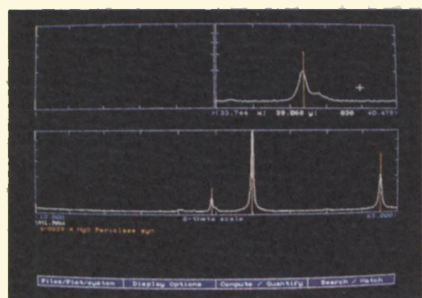
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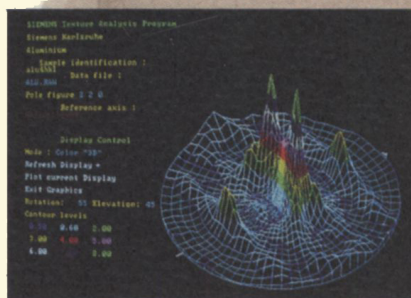
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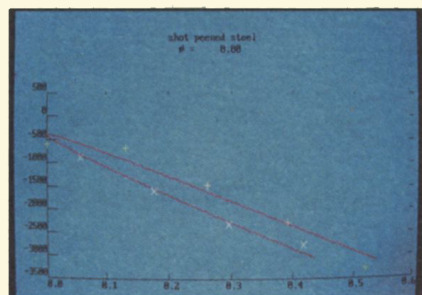
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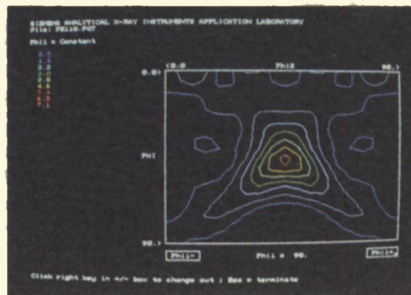
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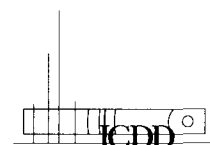
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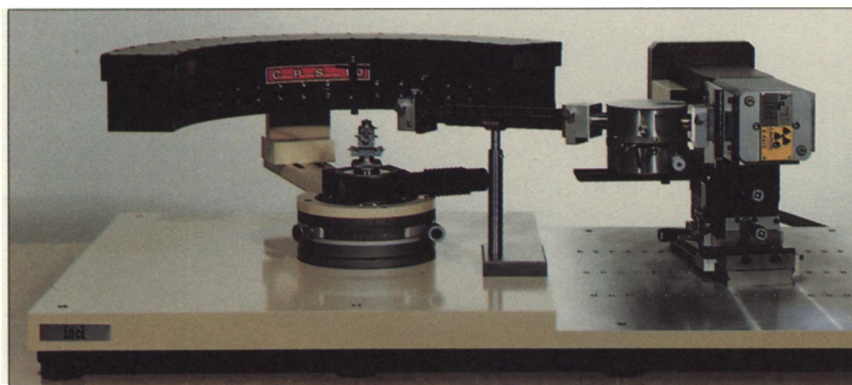
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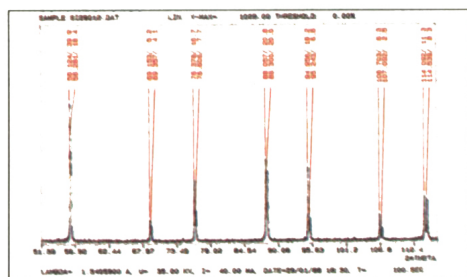
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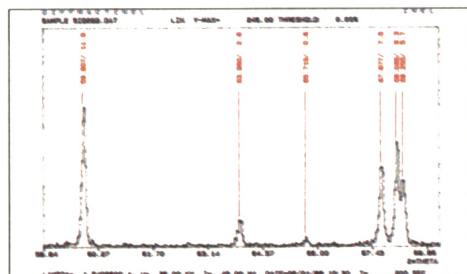
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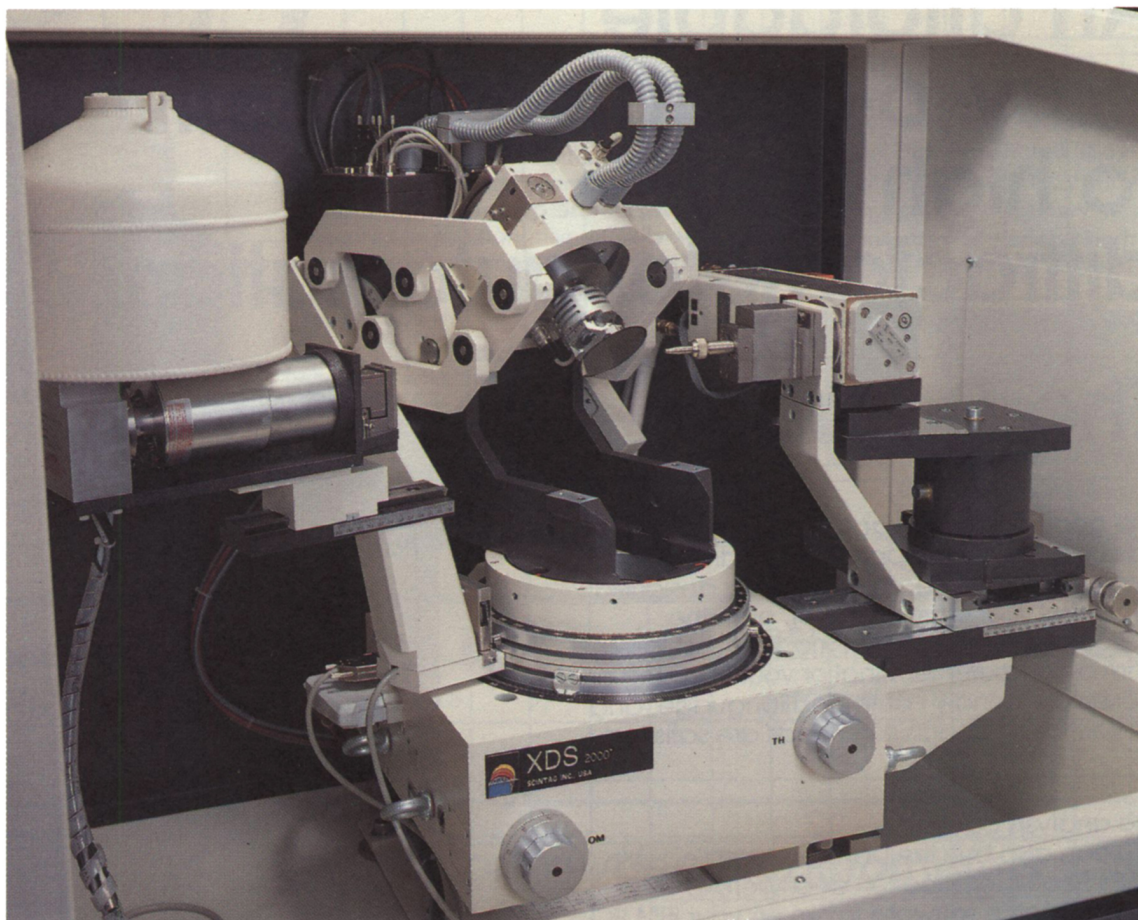
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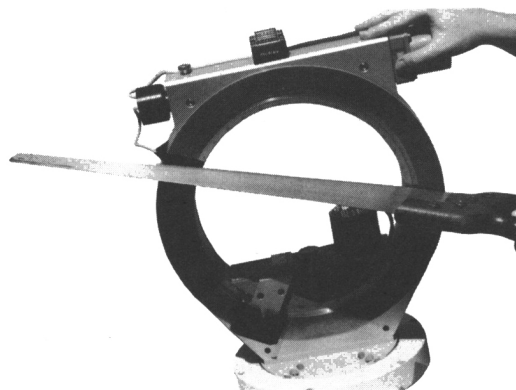
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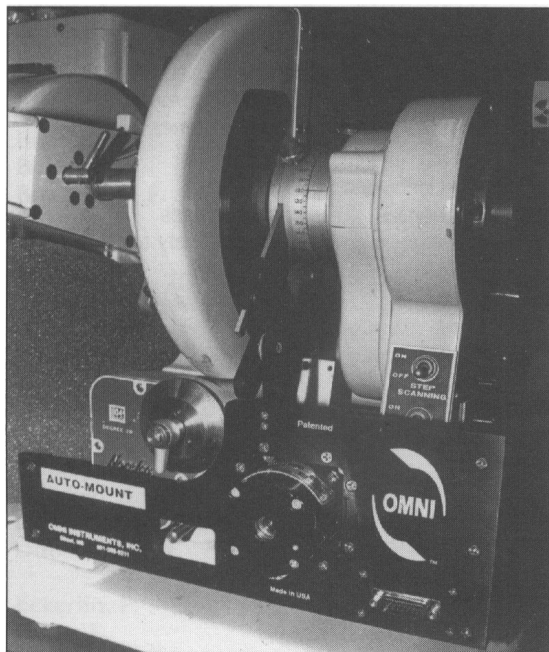


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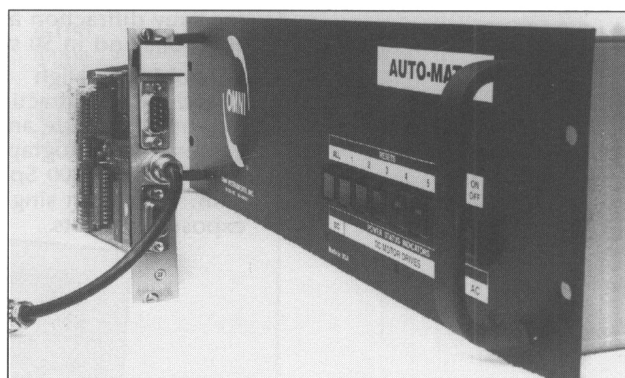
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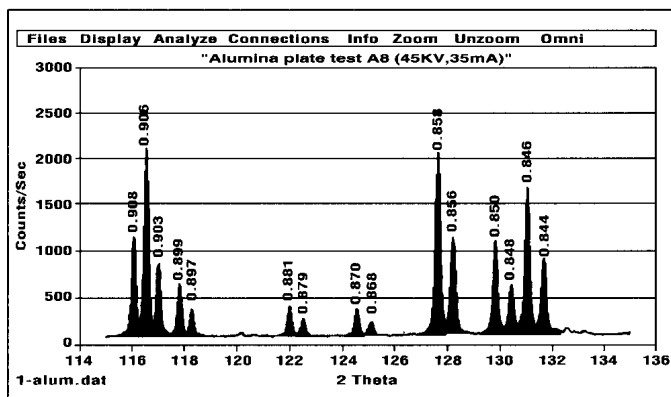
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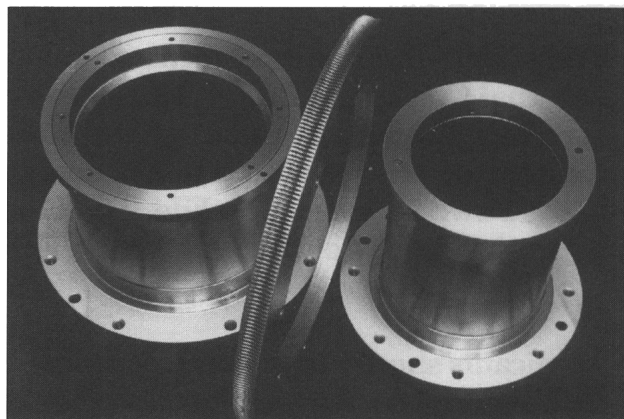


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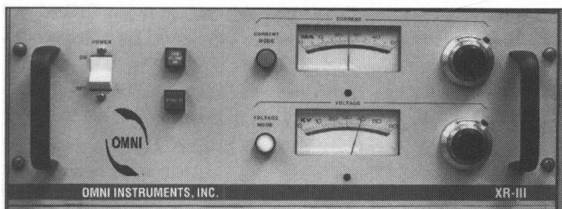
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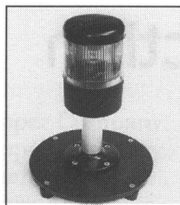


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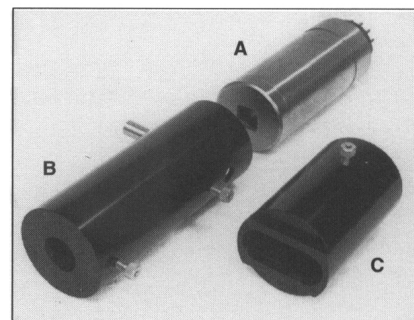
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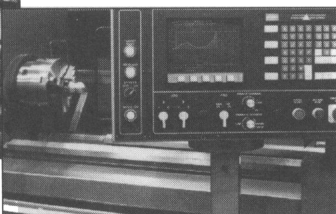
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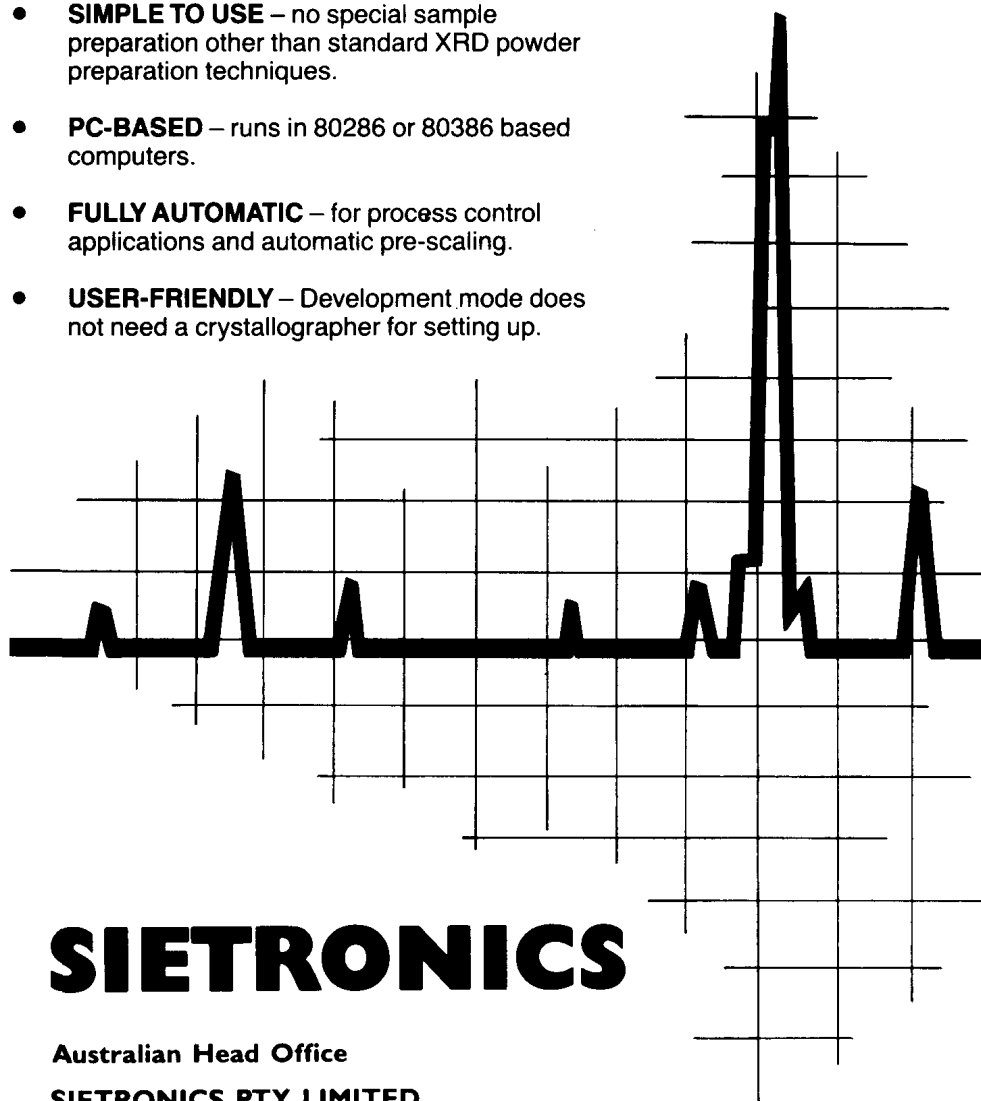
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PD7

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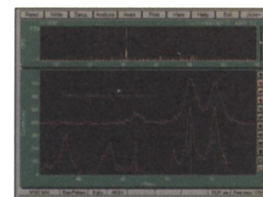
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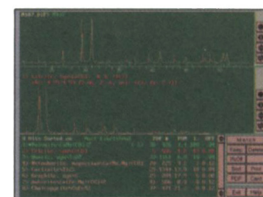


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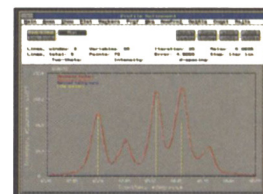
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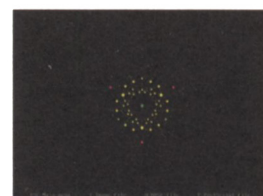
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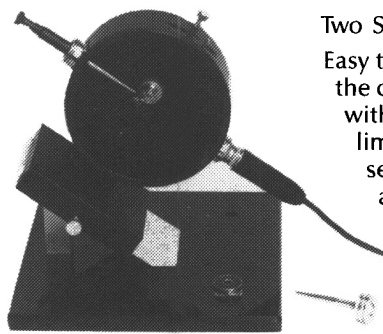
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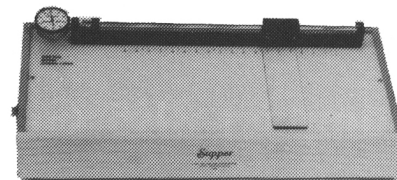


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PD9

XRD Clinic

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The 1992 XRD Clinic will be held at
Swarthmore College, Swarthmore,
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Session I — June 15-19, 1992

Fundamentals of X-ray Powder Diffraction, with theoretical discussion of instrumentation (both diffractometer and camera methods), specimen preparation, data acquisition, and qualitative phase analysis.

Session II — June 22-26, 1992

Advanced Methods in Powder Diffraction, with emphasis on computer-based methods of data collection and interpretation, both for qualitative and quantitative phase analysis.

XRF Clinic

ICDD Clinic on X-ray Fluorescence Spectrometry

The 1992 XRF Clinic will be held at
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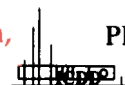
Session I — July 6-10, 1992

Fundamentals of X-ray Fluorescence, with theoretical discussion of instrumentation for wavelength and energy dispersive spectrometry, specimen preparation, and simple quantitative methods.

Session II — July 13-17, 1992

Detailed Discussion of X-ray Fluorescence, with an emphasis on quantitative methods and use of automated X-ray spectrometers.

For more information, contact Theresa Maguire—International Centre for Diffraction Data,
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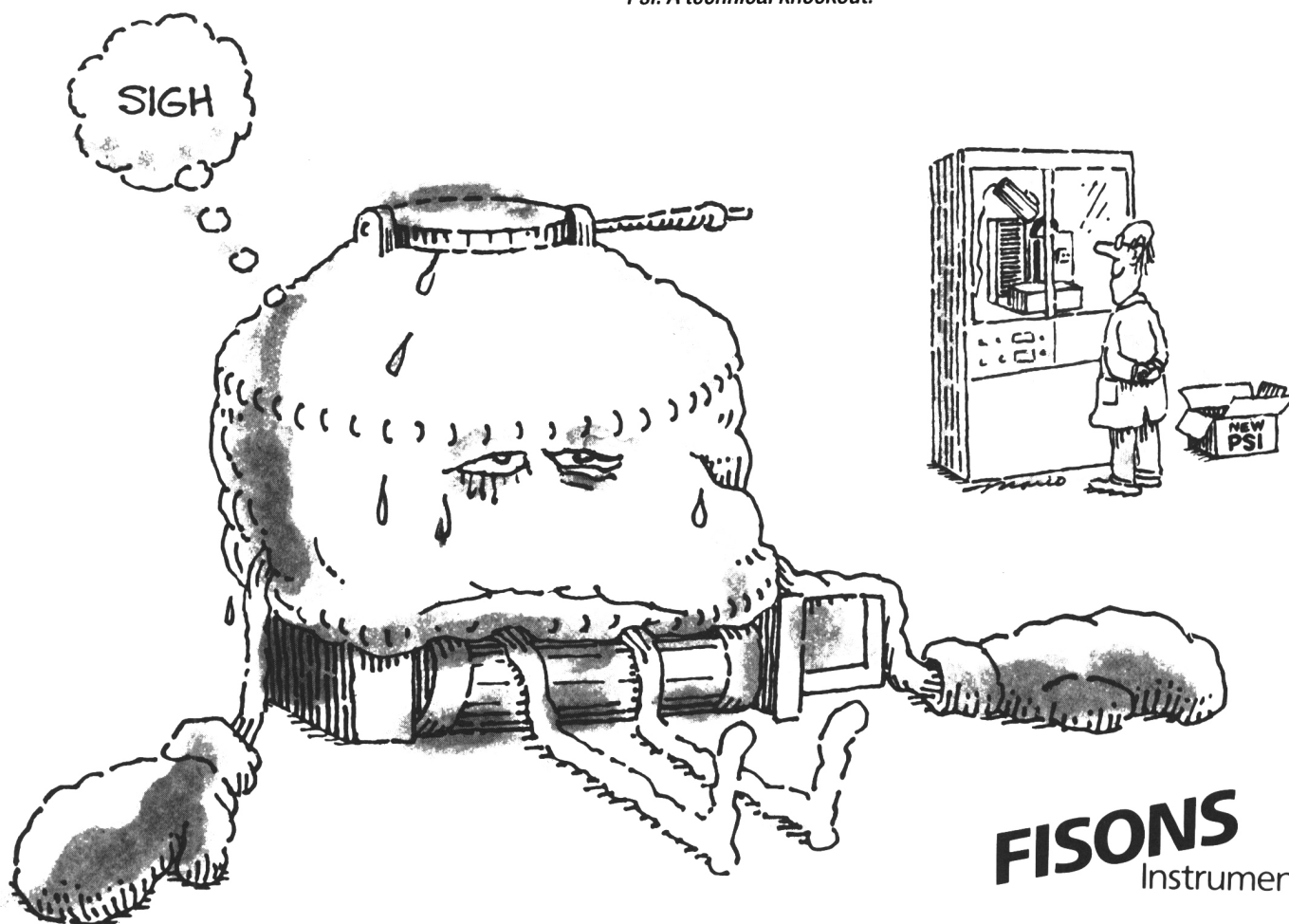
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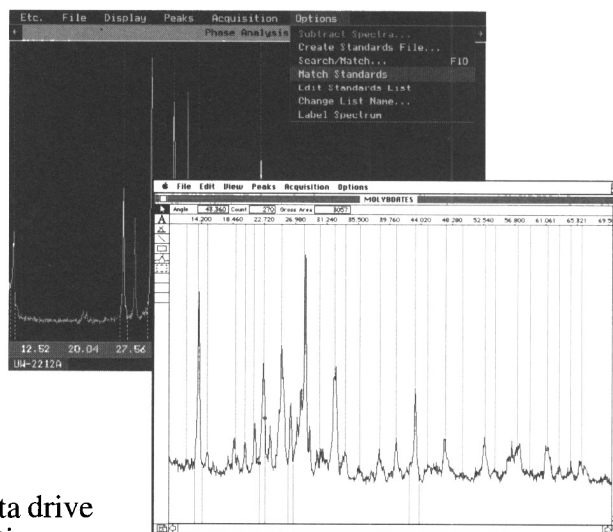
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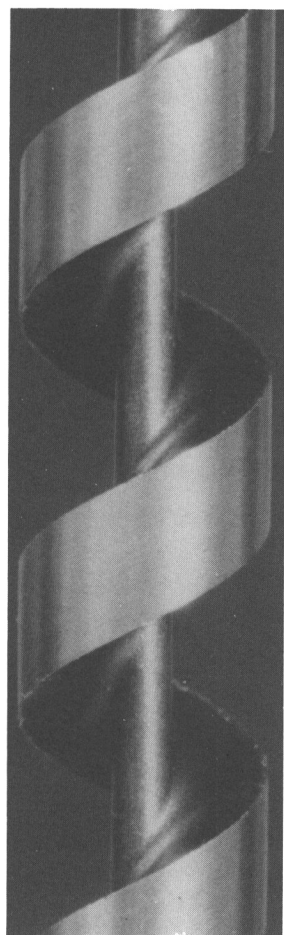
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PD12



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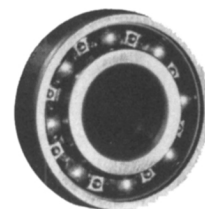
Materials researchers will find this new metallurgical book invaluable in their studies; its organization, selection of materials and use of alphabetical formulae is similar to that of Pearson and Villars and Calvert. The 1990 Metals & Alloys Index Book is designed to be used independently or in conjunction with the Powder Diffraction File (PDF). There are four indexes: the first two provide all materials in the Metals and Alloys PDF and the remaining two contain supporting data.

- **The Alphabetical Formula Index** brings together all entries containing a given element in alphabetical formula order. It has n entries for an n-component material and, to simplify reading the index, a straight-line format for the element being sorted. Chemical knowledge can thus be used to make identification easier.
- **The Pearson Symbol Code Index** has all entries arranged in Pearson Symbol order. Hence, the user can easily find all of the materials with a given structure, and, if desired, compare their atomic contents and lattice parameters. The latter are given for the standard Crystal Data setting to aid in structural comparisons.
- **The Common Names Index** permits cross-referencing of common metallurgical names such as austenite or cementite to the appropriate PDF data. It also has the cross-references for many mineral names that have found their way into metallurgical usage. Certain other useful names (e.g. Zintl phases) may also be found here.
- **The Strukturbericht Symbol Index** provides cross-referencing between Strukturbericht Symbols and the equivalent Pearson Symbols and Structure Prototypes. This index includes those structures for which Strukturbericht Symbols have been assigned and which are likely to be encountered in the metallurgical literature.

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PD13

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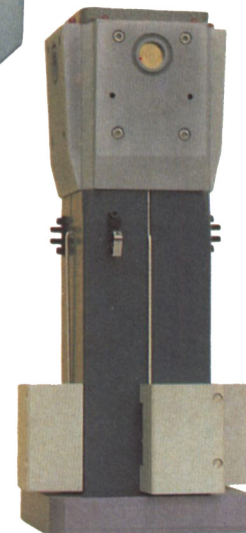
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TECHNICAL SPECIFICATIONS

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* Max current	: 60 mA
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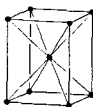
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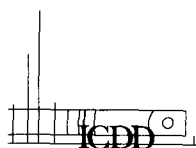


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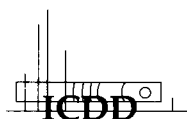
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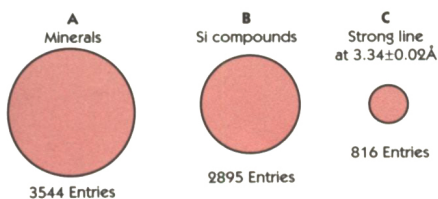


PD18

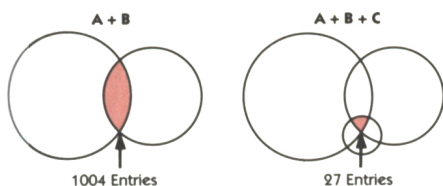
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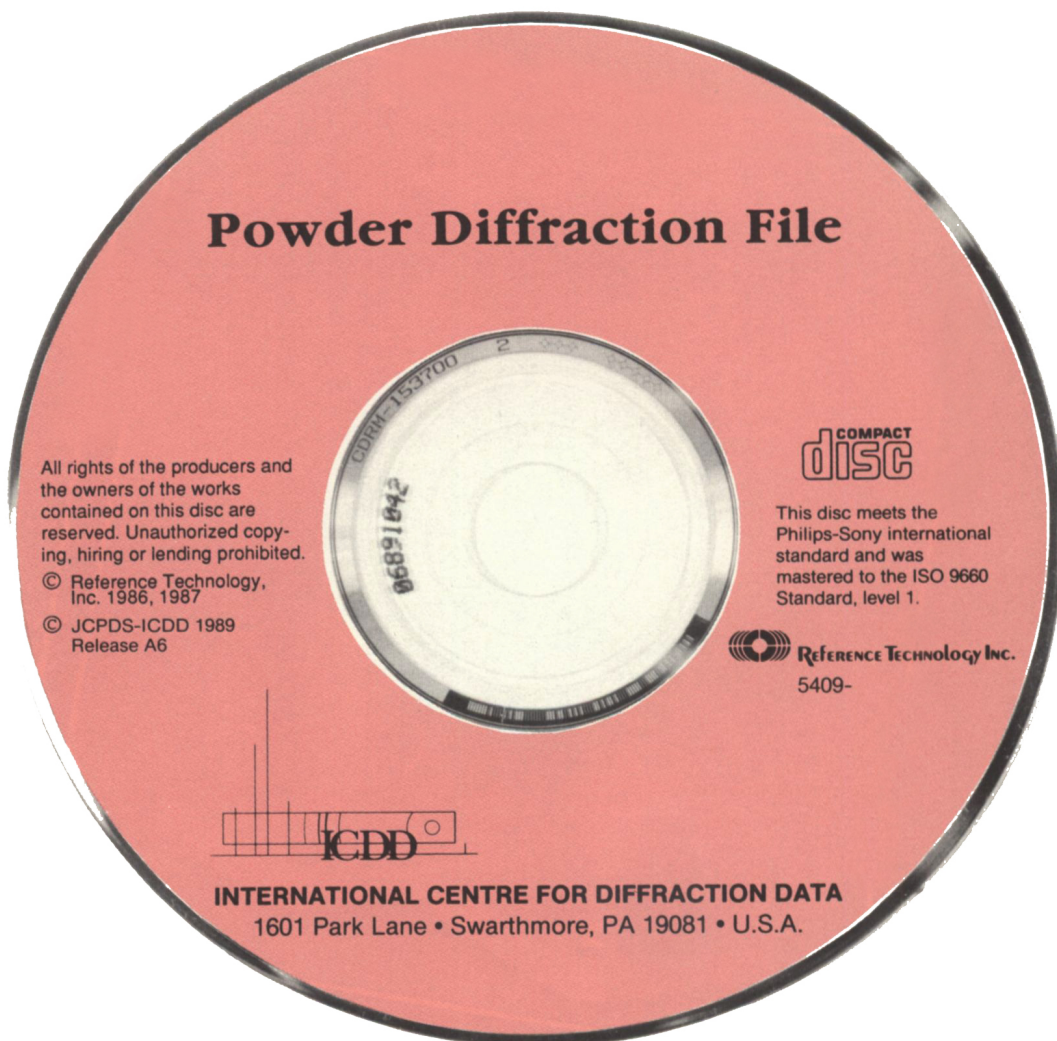
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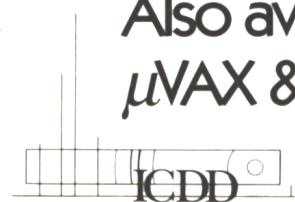
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Editorial On Editorials

As I sit at my typewriter (nowadays the computer) to prepare the editorial for this issue of *Powder Diffraction*, I wonder what role these editorials have in promoting the field of diffraction analysis. In the past, editorials have been used to announce meetings and workshops of interest to the readership. They have tried to promote participation in activities of the International Centre for Diffraction Data and other organizations or in projects being undertaken by individuals such as collecting users input to data compilations and surveys. Sometimes, guest editorials announce important information such as new nomenclature and thoughts on establishing criteria for evaluating powder data. As Editor in Chief, I have also used this column to announce changes in the staff of *Powder Diffraction* and to thank departing associates for their valuable contributions.

In my thoughts at the moment I wonder how often these columns are actually read. Over the years I have really had very few comments from readers about remarks made in these editorials. When questions have been presented by me very few responses have been received. I know what an effort it is to take pen in hand (or computer) and to put one's thoughts on paper for transmittal. Very few people, and even fewer scientists, like to write anything. Now, the telephone or E-mail replaces the formal document. E-mail requires the user to overcome system protocols and computer idiosyncrasies, especially returned mail because of address difficulties. The telephone often encounters the recording machine when the recipient is out or refuses to pick up the receiver. All of these barriers discourage further correspondence and shorten the messages that are actually delivered. Even when I have been at meetings, personal communications with respect to editorials have been few. Is this response really indicative of the influence of these editorials?

Using this editorial to prompt your input, I am soliciting your comments on editorials. Do you read them and do they convey the type of information that is useful or interesting to you? Do you have suggestions for topics for future editorials. Would you like to prepare an editorial on some topic? Guest editorials are welcome at any time. In fact, I would like to en-

courage any reader with an editorial topic to contact me with either a manuscript or pertinent information for me to develop the editorial.

How should you transmit your comments? There are four alternatives: My address is on the title page of this issue. My E-mail address is DKS1@PSUVM.PSU.EDU and my phone number is (814) 865-5782. If you prefer to write by wire, my FAX number is (814) 863-7845. I admit to having an answering machine on my telephone, and I am not always in the office waiting for it to ring. However, I do return calls even if I also encounter answering machines. I have been known to play several cycles of telephone tag before completing the information transfer. Persistence usually wins out. If I receive ten responses to this request, I will consider my requests successfully answered.

Another item to mention in this editorial is to encourage authors to submit manuscripts to the nearest Regional Editor. With the addition of Hideo Toraya, *Powder Diffraction* now has editors in the major geographical regions currently producing articles for the journal. Regional editors allow the most efficient processing of your manuscript primarily because of the proximity of author and editor. It also opens the pool of reviews. As an editor, I like to avoid using the same reviewer more than twice a year, and I try to avoid mailings overseas unless the reviewer is unusually appropriate for the subject being discussed. FAX is a marvelous invention, especially for overseas correspondence, but it is not appropriate for frequent mailings.

Manuscripts involving new powder diffraction data should be submitted directly to G.J. McCarthy, Editor for Diffraction Data. Direct submission to him speeds up the consideration of your manuscript for publication. Submission of the data in a manuscript constitutes submission of the data to ICDD, because all data are sent into the ICDD for computer data review. PDF numbers will rarely be assigned for these data sets because the timing of the manuscript does not always correspond the the packaging of the active set for the Powder Diffraction File.

Please let me hear from you on the subject of editorials.

Deane K. Smith
Editor in Chief